

# MSKSEMI 美森科

SEMICONDUCTOR



ESD



TVS



TSS



MOV



GDT



PLED

## 5P06-MS

Product specification

## Description

The 5P06-MS is the high cell density trench P-ch MOSFETs, which provides excellent R<sub>DS(on)</sub> and efficiency for most of the small power switching and load switch applications.

The 5P06-MS meet the RoHS and Green Product requirement with full function reliability approved.

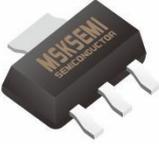
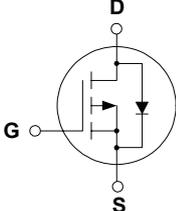
## Product Summary

<b>BVDSS</b>	-60V
<b>R<sub>DS(on)</sub></b>	110mΩ
<b>ID</b>	-5A

## FEATURE

- Green Device Available
- Super Low Gate Charge
- Excellent CdV/dt effect decline
- Advanced high cell density Trench technology

## Reference News

PACKAGE OUTLINE	PIN CONFIGURATION	Marking
 <p>SOT-223</p>		

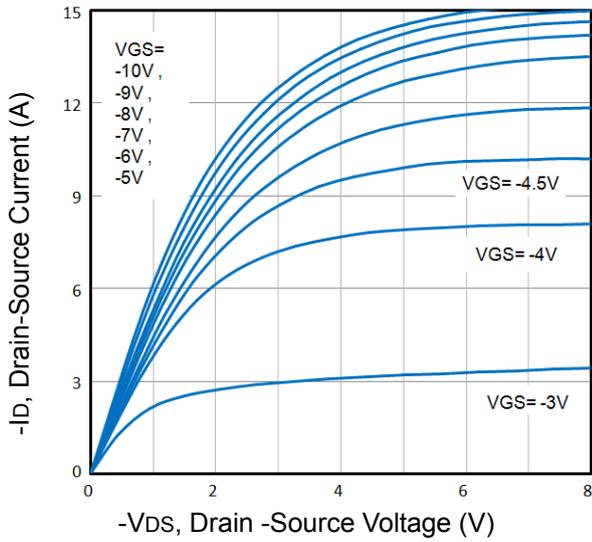
## Absolute Maximum Ratings (T<sub>A</sub>=25°C unless otherwise noted)

Parameter	Symbol	Value	Unit
Drain-Source voltage	<b>V<sub>DS</sub></b>	-60	V
Gate-Source voltage	<b>V<sub>GS</sub></b>	±20	
Continuous Drain Current	<b>I<sub>D</sub></b>	-5.0	A
Pulsed Drain Current <sup>1</sup>	<b>I<sub>DM</sub></b>	-5.2	A
Power Dissipation	<b>P<sub>D</sub></b>	1	W
Junction Temperature	<b>T<sub>J</sub></b>	150	°C
Storage Temperature	<b>T<sub>STG</sub></b>	-55~ 150	°C
Thermal Resistance from Junction to Ambient <sup>2</sup>	<b>R<sub>θJA</sub></b>	125	°C/W

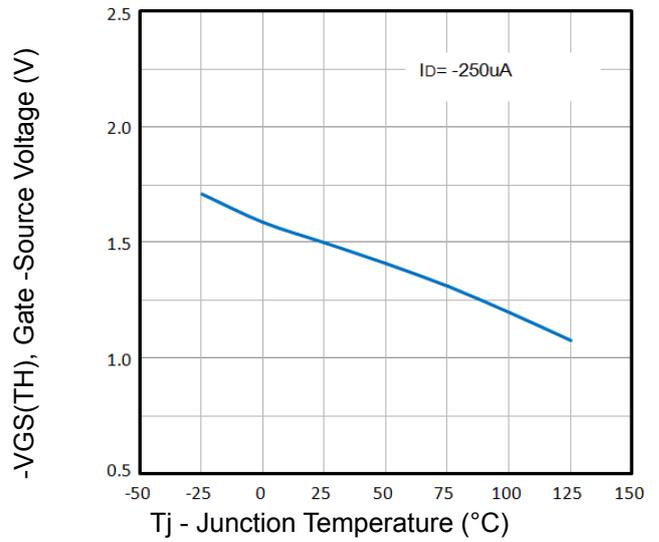
**Electrical Characteristics (T = 25°C unless otherwise noted)**

Symbol	Parameter	Condition	Min	Typ	Max	Unit
<b>Static Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise stated)</b>						
V <sub>(BR)DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V I <sub>D</sub> =-250μA	-60	--	--	V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current(T <sub>A</sub> =25°C)	V <sub>DS</sub> =-60V, V <sub>GS</sub> =0V	--	--	-1	μA
	Zero Gate Voltage Drain Current(T <sub>A</sub> =125°C)	V <sub>DS</sub> =-60V, V <sub>GS</sub> =0V	--	--	-100	uA
I <sub>GSS</sub>	Gate-Body Leakage Current	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V	--	--	±100	nA
V <sub>GS(TH)</sub>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =-250μA	-1.0	-1.5	-2.5	V
R <sub>DS(ON)</sub>	Drain-Source On-State Resistance②	V <sub>GS</sub> =-10V, I <sub>D</sub> =-2A	--	110	180	mΩ
R <sub>DS(ON)</sub>	Drain-Source On-State Resistance②	V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-1A	--	150	200	mΩ
<b>Dynamic Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise stated)</b>						
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> =-30V, V <sub>GS</sub> =0V, f=1MHz	--	310	--	pF
C <sub>oss</sub>	Output Capacitance		--	22	--	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		--	15	--	pF
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> =-30V I <sub>D</sub> =-2A, V <sub>GS</sub> =-10V	--	5.4	--	nC
Q <sub>gs</sub>	Gate Source Charge		--	1.1	--	nC
Q <sub>gd</sub>	Gate Drain Charge		--	1.6	--	nC
<b>Switching Characteristics</b>						
t <sub>d(on)</sub>	Turn on Delay Time	V <sub>DD</sub> =-30V, I <sub>D</sub> =-2A, R <sub>G</sub> =3.3Ω, V <sub>GS</sub> =-10V	--	41	--	ns
t <sub>r</sub>	Turn on Rise Time		--	22	--	ns
t <sub>d(off)</sub>	Turn Off Delay Time		--	25	--	ns
t <sub>f</sub>	Turn Off Fall Time		--	32	--	ns
<b>Source Drain Diode Characteristics</b>						
I <sub>SD</sub>	Source drain current(Body Diode)	T <sub>A</sub> =25°C	--	--	-2.0	A
V <sub>SD</sub>	Forward on voltage②	T <sub>J</sub> =25°C, I <sub>SD</sub> =-2A, V <sub>GS</sub> =0V	--	-0.84	-1.2	V

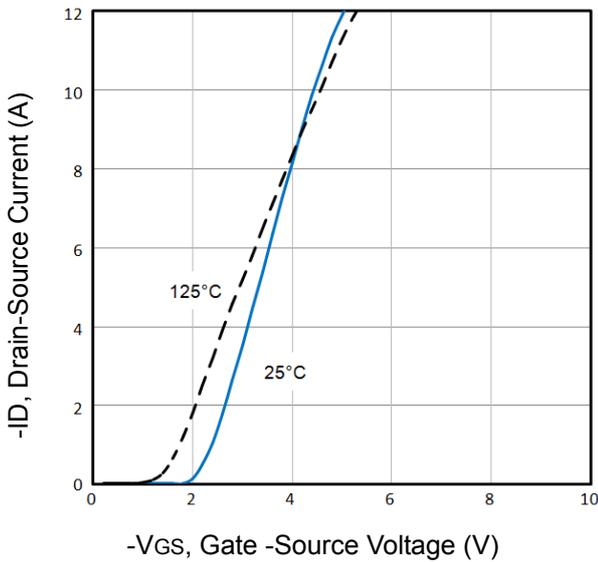
**Typical Characteristics**



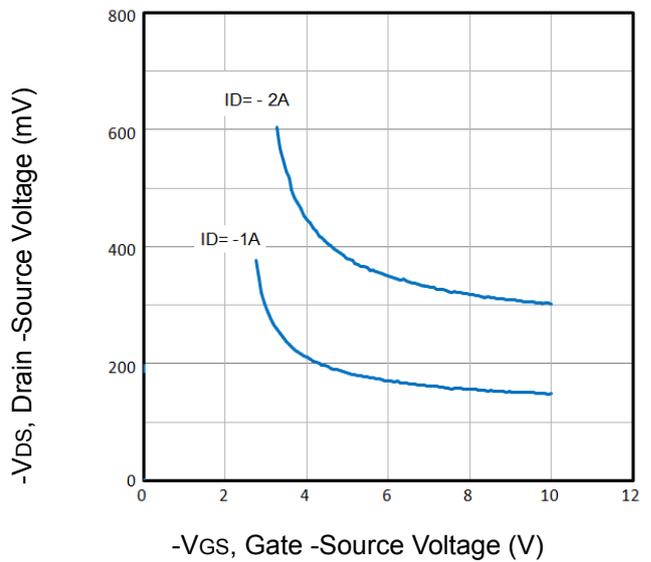
**Fig1.** Typical Output Characteristics



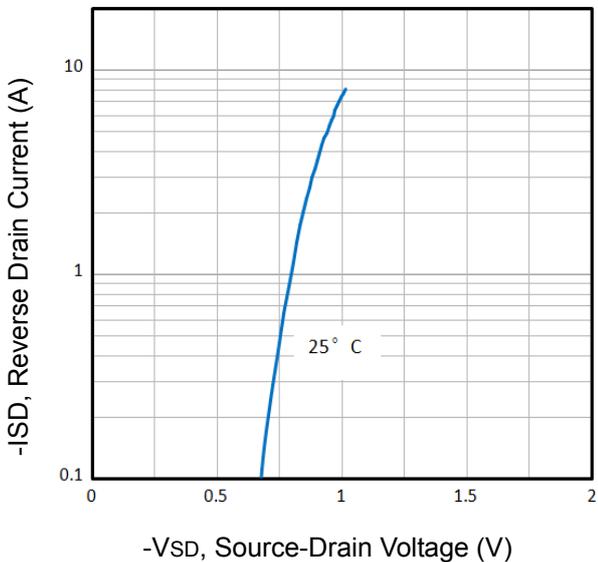
**Fig2.** Normalized Threshold Voltage Vs. Temperature



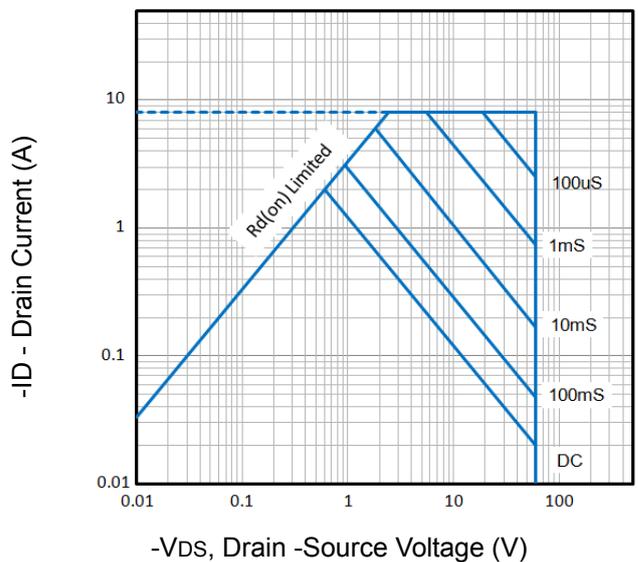
**Fig3.** Typical Transfer Characteristics



**Fig4.** Drain-Source Voltage vs Gate-Source Voltage

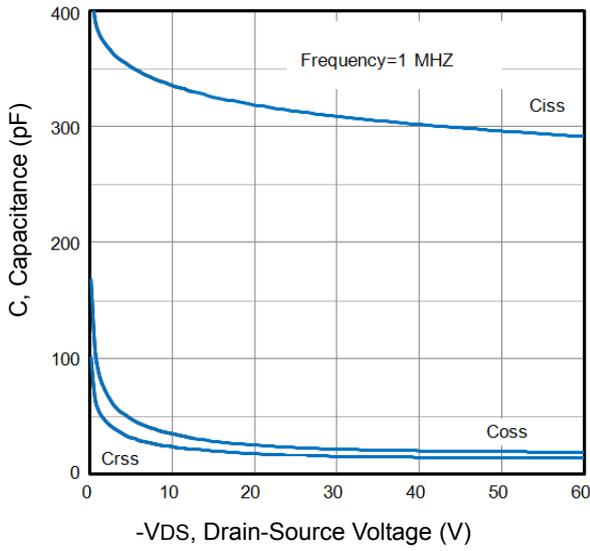


**Fig5.** Typical Source-Drain Diode Forward Voltage

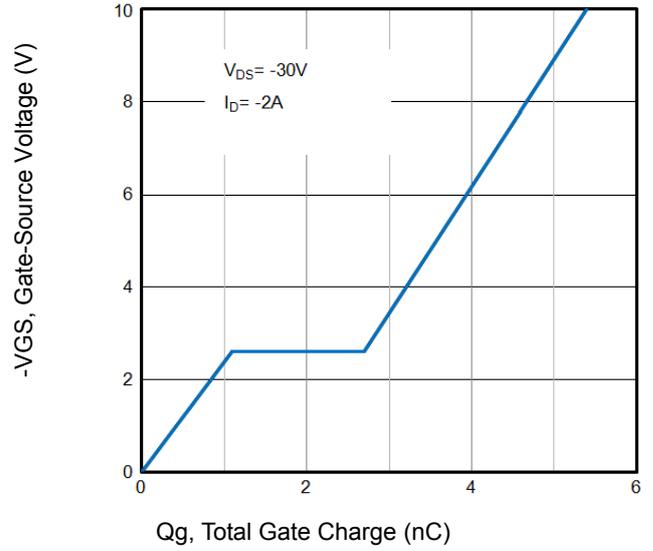


**Fig6.** Maximum Safe Operating Area

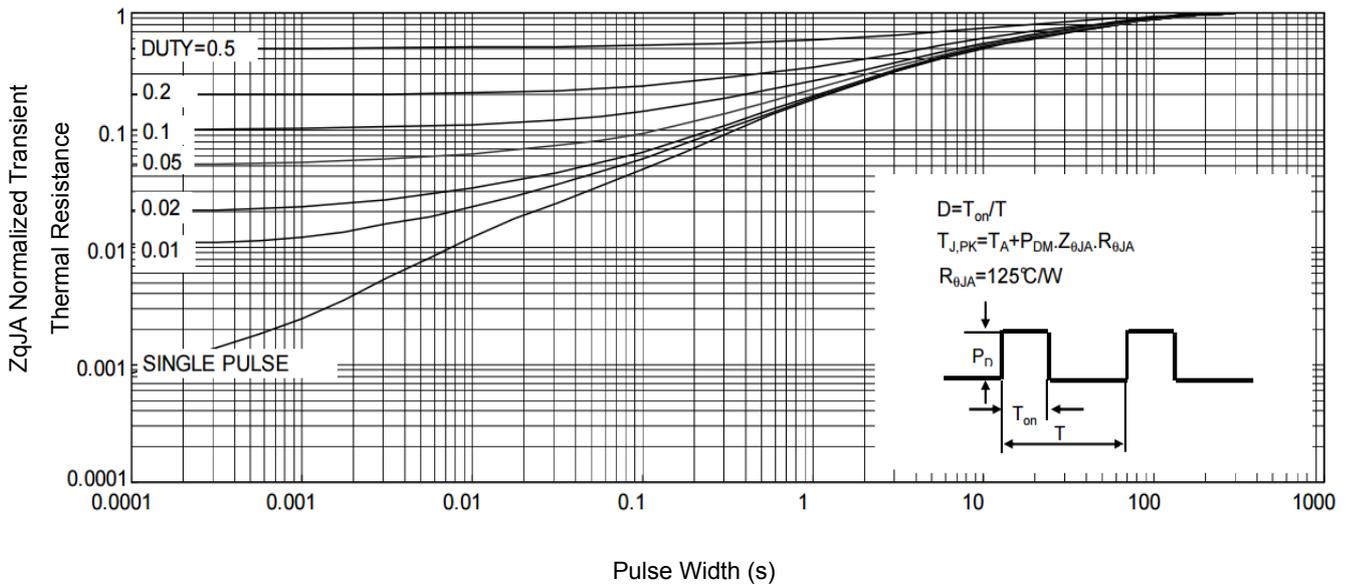
Typical Characteristics



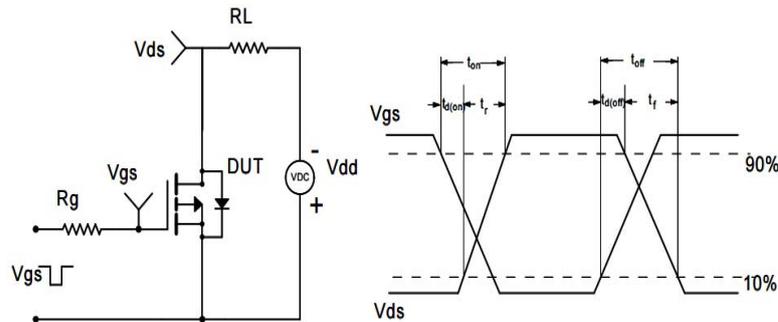
**Fig7.** Typical Capacitance Vs. Drain-Source Voltage



**Fig8.** Typical Gate Charge Vs. Gate-Source Voltage

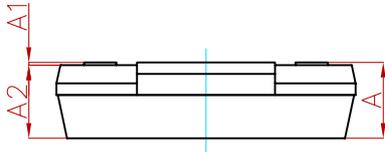
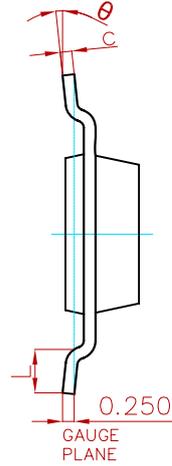
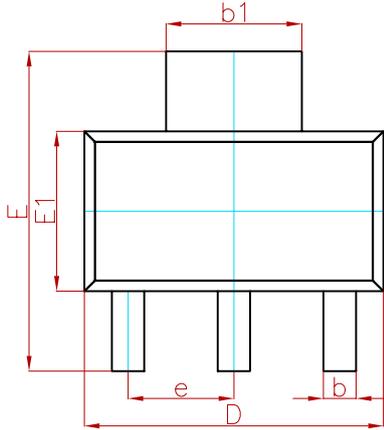


**Fig9.** Normalized Maximum Transient Thermal Impedance



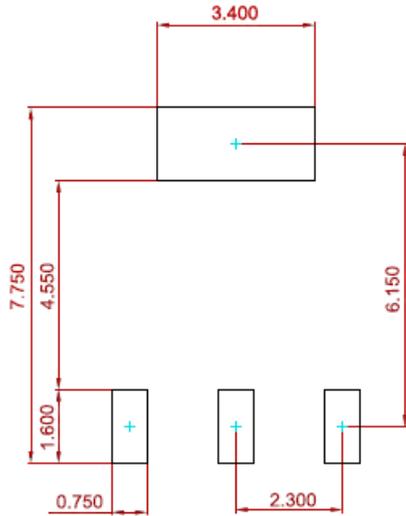
**Fig10.** Switching Time Test Circuit and waveforms

**PACKAGE MECHANICAL DATA**



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	—	1.800	—	0.071
A1	0.020	0.100	0.001	0.004
A2	1.500	1.700	0.059	0.067
b	0.660	0.840	0.026	0.033
b1	2.900	3.100	0.114	0.122
c	0.230	0.350	0.009	0.014
D	6.300	6.700	0.248	0.264
E	6.700	7.300	0.264	0.287
E1	3.300	3.700	0.130	0.146
e	2.300(BSC)		0.091(BSC)	
L	0.750	—	0.030	—
$\theta$	0°	10°	0°	10°

**Suggested Pad Layout**



**Note:**

1. Controlling dimension: in millimeters.
2. General tolerance:  $\pm 0.050$ mm.
3. The pad layout is for reference purposes only.

**REEL SPECIFICATION**

P/N	PKG	QTY
5P06-MS	SOT-223	1000

## Attention

- Any and all MSKSEMI Semiconductor products described or contained herein do not have specifications that can handle applications that require extremely high levels of reliability, such as life-support systems, aircraft's control systems, or other applications whose failure can be reasonably expected to result in serious physical and/or material damage. Consult with your MSKSEMI Semiconductor representative nearest you before using any MSKSEMI Semiconductor products described or contained herein in such applications.
- MSKSEMI Semiconductor assumes no responsibility for equipment failures that result from using products at values that exceed, even momentarily, rated values (such as maximum ratings, operating condition ranges, or other parameters) listed in products specifications of any and all MSKSEMI Semiconductor products described or contained herein.
- Specifications of any and all MSKSEMI Semiconductor products described or contained herein stipulate the performance, characteristics, and functions of the described products in the independent state, and are not guarantees of the performance, characteristics, and functions of the described products as mounted in the customer's products or equipment. To verify symptoms and states that cannot be evaluated in an independent device, the customer should always evaluate and test devices mounted in the customer's products or equipment.
- MSKSEMI Semiconductor strives to supply high-quality high-reliability products. However, any and all semiconductor products fail with some probability. It is possible that these probabilistic failures could give rise to accidents or events that could endanger human lives, that could give rise to smoke or fire, or that could cause damage to other property. When designing equipment, adopt safety measures so that these kinds of accidents or events cannot occur. Such measures include but are not limited to protective circuits and error prevention circuits for safe design, redundant design, and structural design.
- In the event that any or all MSKSEMI Semiconductor products (including technical data, services) described or contained herein are controlled under any of applicable local export control laws and regulations, such products must not be exported without obtaining the export license from the authorities concerned in accordance with the above law.
- No part of this publication may be reproduced or transmitted in any form or by any means, electronic or mechanical, including photocopying and recording, or any information storage or retrieval system, or otherwise, without the prior written permission of MSKSEMI Semiconductor.
- Information (including circuit diagrams and circuit parameters) herein is for example only ; it is not guaranteed for volume production. MSKSEMI Semiconductor believes information herein is accurate and reliable, but no guarantees are made or implied regarding its use or any infringements of intellectual property rights or other rights of third parties.
- Any and all information described or contained herein are subject to change without notice due to product/technology improvement, etc. When designing equipment, refer to the "Delivery Specification" for the MSKSEMI Semiconductor product that you intend to use.